

DATE 12 FEB 2009

- NOTES:

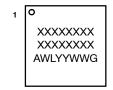
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSIONS: MILLIMETERS.

 3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS. POSITIONAL TOLERANCE APPLIES TO ALL THREE EXPOSED PADS.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.80	1.00	
A1	-	0.05	
А3	0.20 REF		
b	0.18	0.30	
D	8.00 BSC		
D2	3.35	3.55	
D3	2.10	2.30	
E	8.00 BSC		
E2	6.10	6.30	
E3	2.05	2.25	
E4	3.40	3.60	
е	0.50 BSC		
G	3.10		
K	0.20	-	
L	0.30	0.50	
L1		0.15	

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location Α

= Wafer Lot WL = Year YY = Work Week WW G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part

Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DESCRIPTION:	QFN56 8x8, 0.5P		PAGE 1 OF 1

DIMENSIONS: MILLIMETERS

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